Power MOSFET

30 V, 12 A, Single N-Channel, SO-8

Features

- Low R_{DS(on)}
- Low Gate Charge
- Standard SO-8 Single Package
- Pb-Free Package is Available

Applications

- Notebooks, Graphics Cards
- Synchronous Rectification
- High Side Switch
- DC-DC Converters

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage	Gate-to-Source Voltage			±20	V
Continuous Drain	Steady	T _A = 25°C	I _D	10	Α
Current (Note 1)	State	T _A = 85°C		7.2	
	t ≤ 10 s	T _A = 25°C		12	
Power Dissipation (Note 1)	Steady State	T _A = 25°C	P _D	1.52	W
	$t \leq 10 s$			2.3	
Continuous Drain	Steady	T _A = 25°C	I _D	7.4	Α
Current (Note 2)	State	T _A = 85°C		5.3	
Power Dissipation (Note 2)		T _A = 25°C	P _D	0.85	W
Pulsed Drain Current	ain Current t _p = 10 μs			36	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	-55 to 150	°C
Source Current (Body Diode)			IS	3.0	Α
Single Pulse Drain-to-Source Avalanche Energy (V_{DD} = 25 V, V_{GS} = 10 V, Peak I _L = 7.5 A, L = 10 mH, R _G = 25 Ω)			E _{AS}	210	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	82	°C/W
Junction-to-Ambient – $t \le 10 \text{ s (Note 1)}$	$R_{\theta JA}$	55	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	147	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surface mounted on FR4 board using 1 in sq pad size
- (Cu area = 1.127 in sq [1 oz] including traces).
- 2. Surface mounted on FR4 board using the minimum recommended pad size.

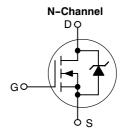
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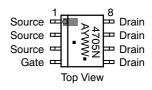
V _{(BR)DSS}	R _{DS(ON)} TYP	I _D MAX (Note 1)
30 V	8.0 mΩ @ 10 V	12 A
30 V	10.5 m Ω @ 4.5 V	12.8



MARKING DIAGRAM/ PIN ASSIGNMENT



SO-8 CASE 751 STYLE 12



4705N = Device Code A = Assembly Location

Y = Year WW = Work Week • Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMS4705NR2	SO-8	2500/Tape & Reel
NTMS4705NR2G	SO-8 (Pb-Free)	2500/Tape & Reel

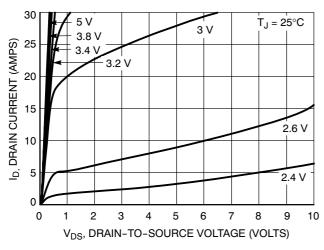
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS			•				
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				15		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	Vcc = 0 V. Vcc =	T _J = 25°C			1.0	μΑ
		V _{GS} = 0 V, V _{DS} = 24 V	T _J = 125°C			50	1
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$				±100	nA
ON CHARACTERISTICS (Note 3)	•		•		•	•	
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$: 250 μA	1.0		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D	= 12 A		8.0	10	mΩ
		V _{GS} = 4.5 V, I _D = 10 A			10.5	14	1
Forward Transconductance	9FS	V _{DS} = 15 V, I _D	= 10 A		19		S
CHARGES, CAPACITANCES AND GATE	RESISTANCE		-		-		-
Input Capacitance	C _{iss}	V _{GS} = 0 V, f = 1.0 MHz, V _{DS} = 24 V			1078		pF
Output Capacitance	C _{oss}				460		1
Reverse Transfer Capacitance	C _{rss}				127		
Total Gate Charge	Q _{G(TOT)}				11	18	nC
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 15 V, I _D = 10 A			1.1		1
Gate-to-Source Charge	Q_{GS}				2.1		1
Gate-to-Drain Charge	Q_{GD}		-		5.8		1
Gate Resistance	R_{G}				1.76	3.5	Ω
SWITCHING CHARACTERISTICS (Note	4)		•		•	•	
Turn-On Delay Time	t _{d(on)}				7.8		ns
Rise Time	t _r	Vce = 10 V. Vnn = 15	V. In = 1.0 A.		4.7		1
Turn-Off Delay Time	t _{d(off)}	$V_{GS} = 10 \text{ V}, V_{DD} = 15$ $R_{G} = 3.0$	Ω		27		1
Fall Time	t _f				17		1
DRAIN-SOURCE DIODE CHARACTERIS	STICS		<u>'</u>		•		-1
Forward Diode Voltage	V_{SD}	$V_{GS} = 0 \text{ V}, I_{S} = 3.0 \text{ A}$	T _J = 25°C		0.73	1.0	V
			T _J = 125°C		0.51		1
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } d_{IS}/d_t = 100 \text{ A/}\mu\text{s,}$ $I_S = 3.0 \text{ A}$			38		ns
Charge Time	t _a				17		1
Discharge Time	t _b				21		1
Reverse Recovery Charge	Q _{RR}				30	1	nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
Switching characteristics are independent of operating junction temperatures.

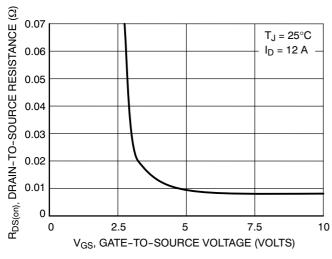
TYPICAL PERFORMANCE CURVES



42 V_{DS} ≥ 10 V 30 V_{DS} ≥ 10 V 12 T_J = 125°C T_J = 25°C T_J = -55°C 0 1 2 3 4 5 V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



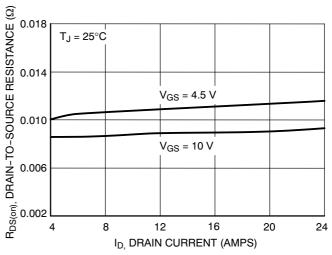
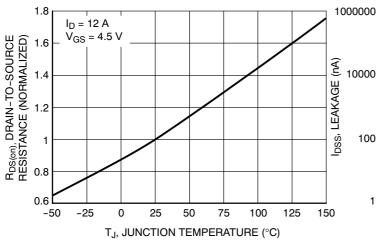


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



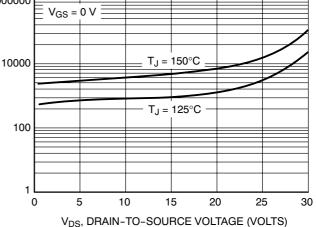
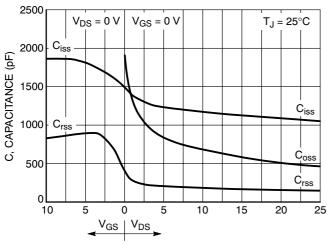


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation

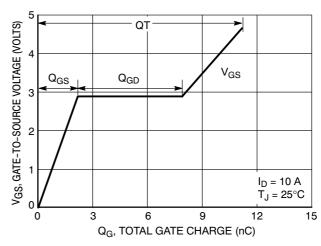


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

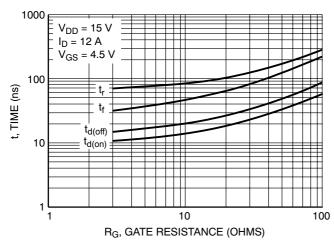


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

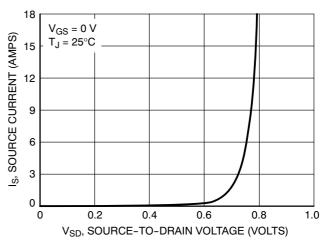


Figure 10. Diode Forward Voltage vs. Current

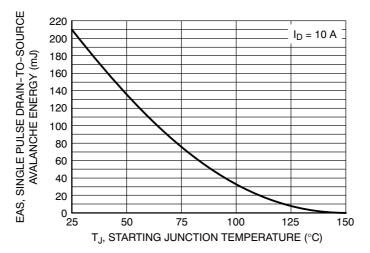
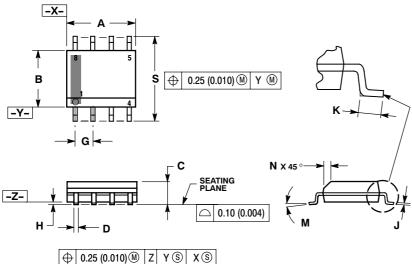


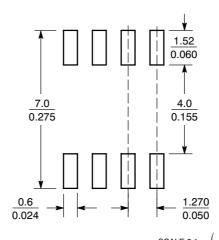
Figure 11. Maximum Avalanche Energy vs. Starting Junction Temperature

PACKAGE DIMENSIONS

SOIC-8 CASE 751-07 **ISSUE AJ**



SOLDERING FOOTPRINT*



mm inches SCALE 6:1

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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NOTES

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE, NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES			
DIM	MIN	MAX	MIN	MAX		
Α	4.80	5.00	0.189	0.197		
В	3.80	4.00	0.150	0.157		
C	1.35	1.75	0.053	0.069		
D	0.33	0.51	0.013	0.020		
G	1.27 BSC		0.05	0 BSC		
Н	0.10	0.25	0.004	0.010		
7	0.19	0.25	0.007	0.010		
K	0.40	1.27	0.016	0.050		
М	0 °	8 °	0 °	8 °		
N	0.25	0.50	0.010	0.020		
S	5.80	6.20	0.228	0.244		

STYLF 12:

- SOURCE PIN 1.
 - SOURCE 2. 3.
 - GATE
 - DRAIN
 - DRAIN 6.
 - DRAIN DRAIN

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